

JEOLink

JEOL USA Newsletter

June 2008

See Us at These Upcoming Meetings and
Tradeshows



Semicon West

Visit the links below to see what JEOL will
be exhibiting:

[Booth #1306 \(South Hall\)](#) AND [Booth #7413](#)

[\(West Hall\)](#)

July 15 - 17, 2008
San Francisco, CA

Microscopy & Microanalysis

[\(M&M\)](#) Booth #1027 and #515

August 4 - 6, 2008
Albuquerque, NM

**Watch for updates on powerful new
products!**

JEOL
**Award-winning
Service & Support**

- Omega Award Winner 8 Consecutive Years
- Largest Service Staff
- Unparalleled Application Support
- Expertise 24/7

2005 Ft. Lauderdale, FL
2006 Ft. Lauderdale, FL
2007 Ft. Lauderdale, FL
2008 Ft. Lauderdale, FL

World Class Excellence
Customer Satisfaction

JEOL

8 Awards in 8 Years! JEOL Wins 8th Omega Award for Customer Service

With a legacy of commitment to customer support, JEOL USA is pleased to accept its 8th award in as many years for excellence in customer satisfaction as judged by our customers. The Omega NorthFace ScoreBoard Award was presented in May at Boston's World Trade Center to 27 qualifying companies, including JEOL and three other companies that qualified for eight consecutive years.

"The NorthFace ScoreBoard Awards recognize organizations who not only offer exemplary

customer service, but who also center their existence on a deep commitment to exceeding customer expectations," said John Alexander Maraganis, president & CEO of Omega. Omega's methodology measures customer satisfaction and loyalty levels for all clients on a 5-point scale a minimum of twice during the year in such categories as technical support, field service, customer service and account management.

"When the Omega Corporation first approached JEOL, it was obvious that a more efficient manner in which to identify customers' concerns and their current level of satisfaction could be established," said JEOL's Vice President of Service, Patrick McGinley.

"The approach to formally survey customers with an independent outside company was then, and is still unique in the microscopy industry. So unique in fact that during the early days, several of JEOL's loyal customers, having recently been contacted by the Omega Corporation, immediately contacted JEOL to alert them that one of their competitors had likely hired an outside company to investigate their service operations. JEOL was delighted to inform them that this was actually part of their own efforts to further improve on their current operations.

"Today the Omega customer satisfaction reports are used in JEOL's daily operations, as well as Regional, National, and Board of Directors' meetings. In fact, over the past several years, the JEOL World Wide Service meetings have included several key presentations that reference these reports."

Several years ago, using the consolidated yearly Omega information, JEOL established the "Manager's Report Card", which is an annual review of the JEOL service managers' individual performances. This has become a friendly internal competition and a strong reminder that personal efforts have a considerable impact on the overall quality of JEOL's service.

Extreme Image



A Pagoda in the Kyoto Moonlight

A five-story pagoda was created out of a Nd-Fe-B permanent magnet using a FIB. The black and white contrast emanating from the pagoda represents magnetic fields generated from the tower of the magnet. The contrast also demonstrates the opposite directions of the magnetic fields. Imaging of the magnetic sample in the STEM mode revealed the magnetic fields. Sample preparation device JEM-9320FIB. TEM/STEM: JEM-2100F.

This micrograph won the Outstanding Award at the 64th Photography Contest of the Japanese Society of Microscopy.

Photographed by Satoshi Yasuhara, Electron Optics Division, JEOL Ltd. and Toshiaki Suzuki, Metrology Inspection Division, JEOL Ltd.

Quick Links

[Invitation to the SEM World](#)

[Guide to Scanning Electron
Microscope Observation](#)

[JEOL USA Online
Products
Resources
Image Gallery](#)

Omega's continuous monitoring of JEOL's performance ensures that they are able to clearly track trends and quickly identify areas of concern revolving around customer satisfaction.

"The quarterly reports keep JEOL focused on their customers, while the action alerts highlight special situations that require immediate attention. Today, JEOL is recognized as the industry leader in customer satisfaction among their competitors," said McGinley.



Members of the Service Department at JEOL USA, Peabody with the 8th consecutive Omega Award for Customer Service. The JEOL USA service organization has 13 district offices throughout the U.S., Mexico, and Canada.



Nikon Trains on JEOL's New NeoScope Benchtop SEM

The introduction of the JEOL NeoScope benchtop SEM fills a need among optical and electron microscopists alike. That's why Nikon Instruments and JEOL USA have joined forces to bring this new microscope to market. In April, Nikon sales engineers attended training on the NeoScope at JEOL's Peabody, Mass. headquarters. In the photo, JEOL's Dr. Natasha Erdman (center) teaches operation of the NeoScope to the class with the aid of a wide screen LCD monitor. SEM training manager Tony Laudate (not shown) taught basic SEM operation.

JEOL USA Mission Statement



Mission Statement

Achieve customer fulfillment and loyalty by delivering outstanding technology and superior support while maintaining a leadership position in the industries and institutions that we serve.

New SEM/FIB Factory Acceptance in Preparation for New Lab at USC



Mr. Sakata of JEOL and Dr. Nutt of USC at the MultiBeam SEM/FIB in Japan

Dr. Steve Nutt, Professor of Materials Science and Director of the new Center of Excellence for Nano-Imaging at the University of Southern California, visited the JEOL factory in Akishima, Japan recently to perform acceptance testing on the new JEOL MultiBeam - the JIB-4500 - a high-performance SEM and micromilling FIB with LaB₆ source.

The MultiBeam will be housed in new laboratory space at USC with a JEOL low vacuum, field emission scanning electron microscope (SEM) and a low vacuum tungsten SEM, as well as a Cross Section Polisher sample processing tool. USC experts in the fields of nanotechnology, biology, materials, and engineering use the new instruments within the shared instrumentation facility.

USC initiatives are emphasizing interdisciplinary collaboration, advancing science and meeting societal needs. The university, in partnership with JEOL, will equip the lab with advanced instrumentation and applications support, to create a center for advancing knowledge and research for both organizations, as well as



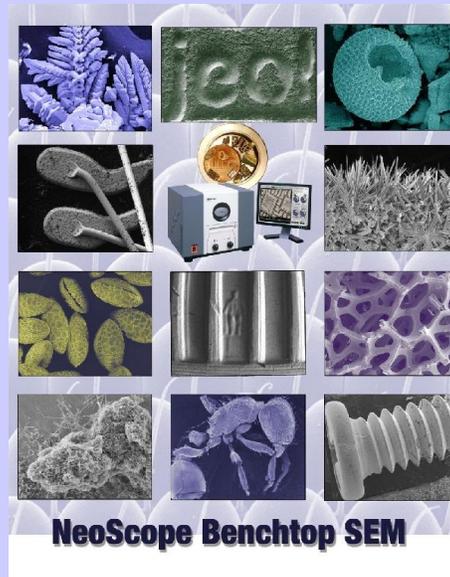
The NeoScope is the only benchtop SEM to offer high depth of field and a choice of parameters for "real world" samples, yet keeps the operation as simple as a digital camera.

Features include:

- low and high vacuum operation
- secondary electron and backscattered electron imaging
- three accelerating voltages
- 10-20,000X magnification

For more information see [press release](#) and visit the [Nikon website](#).

[To see a gallery of images, click here.](#)



To download the Technical Spotlight on NeoScope printed in Advanced Materials and Processes, May 2008, click [here](#).

provide a national demonstration and training facility.

Visit a REALab



[New! Students Learning to Manipulate Molecules at University of New England](#)

[TEM in a BioSafety Level 3 Environment at University of Texas Medical Branch](#)

[The Blue Man - Silver and Selenium Create Mysterious Condition](#)

[Examining Effects of Priority Environmental Contaminants - PBDEs](#)

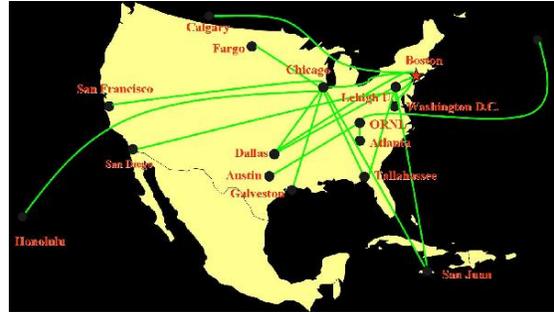
[McCrone's Variety of Analytical Projects](#)

[San Joaquin Delta College Teaches Future EM Technicians](#)

[Art Conservation and Authentication at Philadelphia Museum of Art](#)

[Indiana U. Examines Materials and Biological Specimens with 300 kV TEM](#)

Recent EM Workshops



International Workshop on Remote Electron Microscopy for In Situ Studies

Stanford University

March 31-April 1, 2008

Remote TEM Operation with Sirius presented by JEOL

[Click here for the presentation.](#)



3D Imaging in Electron Microscopy

Presented by JEOL at the [National Institute of Nanotechnology](#) Edmonton, Alberta, Canada

May 26-28, 2008



The Changing World of Electron Microscopy

Presented by JEOL and Hosted by [McCrone](#)

April 15, 2008

JEOL in the News

The Marriage of SEM and FIB

JEOL combines their popular SEM column with high-resolution ion optics in the new [MultiBeam](#). Full story as printed in [R&D Magazine](#).

In Situ Transmission Electron Microscopy

A sequence of aberration-corrected high-angle annular darkfield scanning transmission electron micrographs shows the coalescence of platinum nano particles under the influence of the electron beam at ambient temperature. The images were recorded in intervals of 20 seconds in the JEOL 2200FS located at Oak Ridge National Laboratory. In addition to the platinum nanoparticles, individual platinum atoms and platinum clusters can also be observed on the carbon support. [Full story](#). Request a reprint at jeolink@jeol.com.

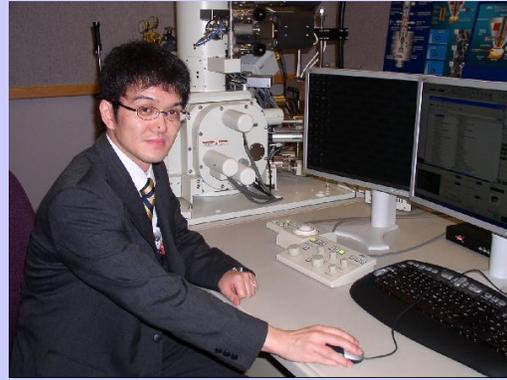
Mapping the Most Complex Structure in the Universe: Your Brain

Harvard scientists have embarked upon an ambitious program to create a circuit diagram of the human brain, with the help of new machines that automatically turn brain tissue into high-resolution neural maps. Full story. [Changing The World One Nano At A Time](#)
Since the University of Arkansas at Little Rock Nanotechnology Center started, researchers have filed three patents. One of those include putting nanostructures inside cancer cells to kill them. The other patents are on solar energy and tissue engineering. [Full story and video](#).

Changing The World One Nano At A Time

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New FE SEM Specialist Joins JEOL USA in Peabody



We welcome Mr. Naoki Kikuchi to the JEOL USA family. Naoki is an Applications Specialist for field emission SEMs. He joined JEOL nine years ago after graduating from MIT (*Muroran Institute of Technology) with a degree in Materials Science. Naoki will be replacing Toshi Kanazawa who will return to Akishima June 26th.

The JEOL Legacy



JEOL Ltd. has produced a video that describes our products and capabilities. Visit our [website](#) "About Us" page and scroll to the video window at the bottom.

SEM Specimen Holders



JEOL USA has the widest offering of sample holders for SEMs. Follow the link above to our Parts Online pages to see the selection. We also work closely with our customers when they have unique requirements. For more information, contact us at salesinfo@jeol.com.